

## Supporting Information

### Precise Control Over the Silica Shell Thickness and Finding the Optimal Thickness for the Peak Heat Diffusion Property of AuNR@SiO<sub>2</sub>

*Wonseok Yang<sup>†</sup>, Sandeep Kaur<sup>‡</sup>, Yong Duk Kim<sup>†</sup>, Jung-Mu Kim<sup>§</sup>, Seung Hee Lee<sup>‡</sup>, and Dong-Kwon Lim<sup>†,\*</sup>*

<sup>†</sup>KU-KIST Graduate School of Converging Science and Technology, Korea University, 145 Anam-ro, Seongbuk-gu, Seoul 02841, Republic of Korea

<sup>‡</sup>Department of Nanoconvergence Engineering and Department of Polymer Nano-Science and Technology, Jeonbuk National University, Jeonju, Jeonbuk 54896, Republic of Korea

<sup>§</sup>Department of Electronic Engineering, Jeonbuk National University, Jeonju, Jeonbuk 54896, Republic of Korea

\*Correspondence: dklim@korea.ac.kr

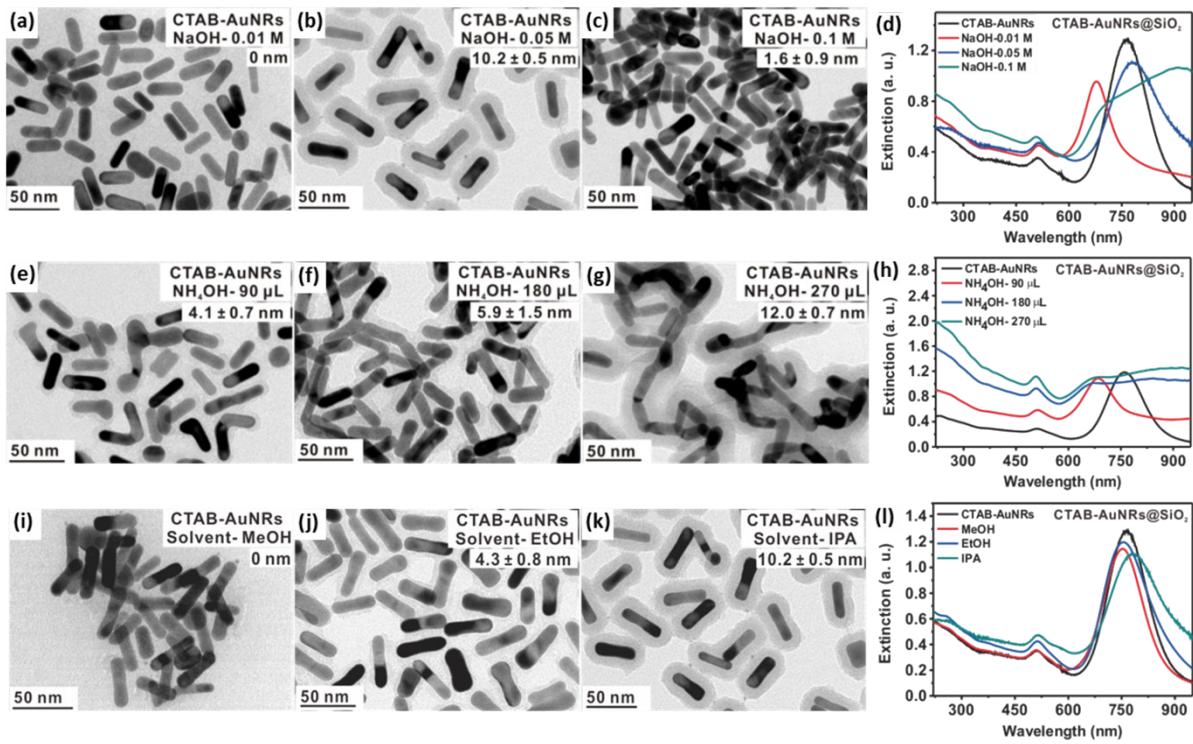
## Materials

HAuCl<sub>4</sub> (99.99%), NaBH<sub>4</sub> (99.9%), cetyltrimethyl ammonium bromide (CTAB; ≥ 99.0%), L-ascorbic acid (≥99.0%), AgNO<sub>3</sub> (≥99.0%), and tetraethyl orthosilicate (TEOS; 99.9%) were purchased from Sigma-Aldrich (St. Louis, MO, USA). NaOH (≥97.0%) and isopropyl alcohol (IPA; 99.5%) were purchased from Daejung Chemical & Metal Co., Ltd. (Shiheung, South Korea). The human tongue squamous carcinoma (HSC-3) cell line was purchased from Sigma-Aldrich (St. Louis, MO, USA). Dulbecco's modified Eagle's medium (DMEM) was obtained from HyClone (Waltham, MA, USA). CellTiter 96® AQ<sub>ueous</sub> One Solution was purchased from Promega (Madison, WI, USA).

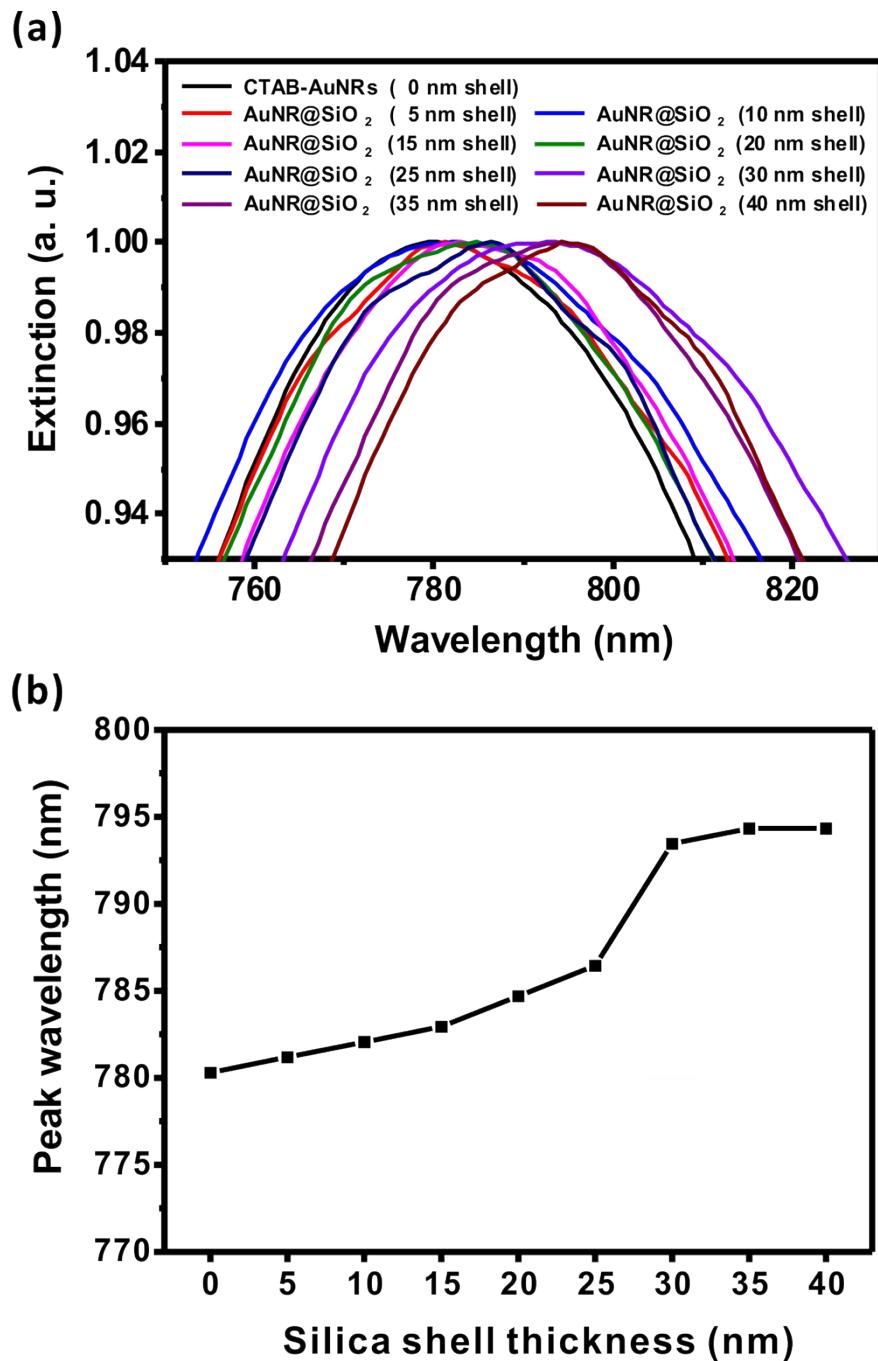
## Instruments

Transmission electron microscopy (TEM, H-7100, Hitachi, Tokyo, Japan) was used for TEM analysis. The extinction spectra were obtained using a UV-visible spectrometer (SCINCO, South Korea). Bright-field and dark-field images were obtained using a microscope (Olympus IX73, Tokyo, Japan) equipped with a dark-field condenser (NA 0.8–0.92; Tokyo, Japan). The photothermal effects were studied using a continuous-wave (CW) diode 808 nm NIR laser with an output power of 4.8 W (Chang-chun New Industries Optoelectronics, China). A thermometer (YF-160A K type, Tenmars Electronics Co., Ltd., Taiwan) and an infrared thermal imaging camera (FLIR C2, FLIR Systems Inc., USA) were used to measure the temperature and obtain thermal imaging, respectively. X-ray diffraction (XRD) measurements were performed using a X-ray diffractometer (SmartLab, Rigaku, Japan) with a Cu K $\alpha$  radiation source (45 kV, 200 mA, wavelength : 1.5412 Å). X-ray photoelectron spectroscopy (XPS) measurements were performed using a X-ray photoelectron spectroscope (X-TOOL, ULVAC-PHI, Japan) with a Ar sputter gun (> 5.0  $\mu$ A, 5 kV). Raman spectra were acquired using an inverted Raman microscope (NOST, South

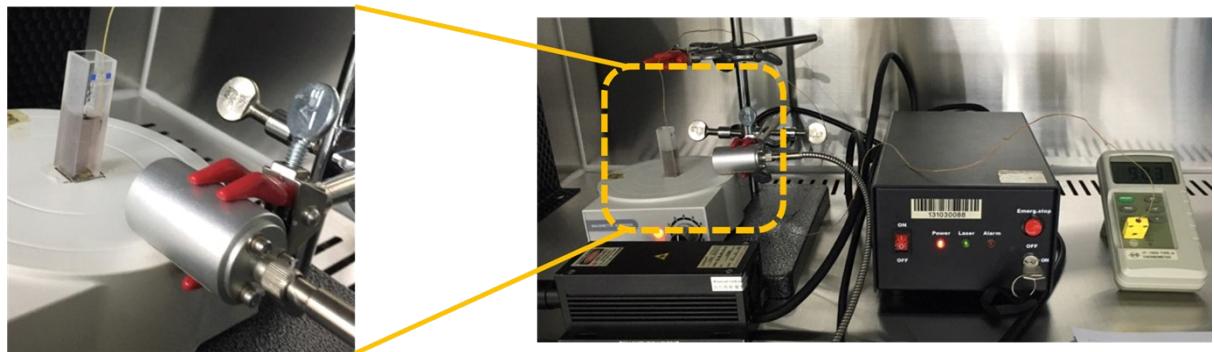
Korea). An Epoch™ Microplate Spectrophotometer (BioTek Inc., Winooski, USA) was used to assess the cell viability.



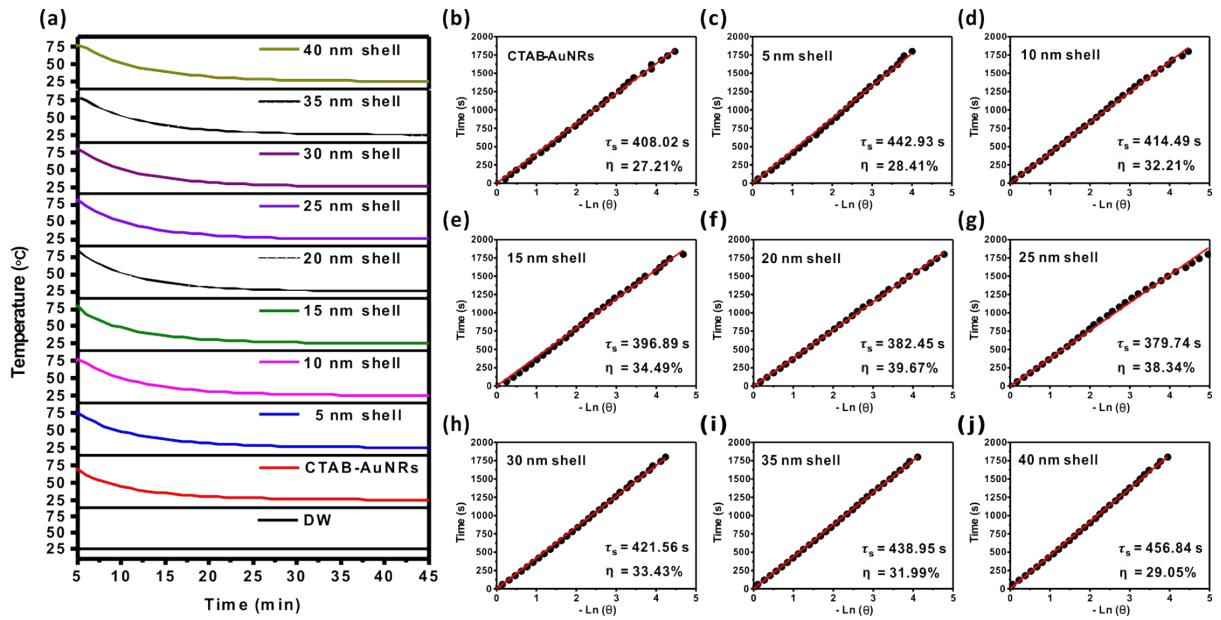
**Figure S1.** TEM images of CTAB-AuNRs@SiO<sub>2</sub> prepared with (a) 0.01 M, (b) 0.05 M, and (c) 0.1 M NaOH, and (d) UV-Visible spectra. TEM images of CTAB-AuNRs@SiO<sub>2</sub> prepared with (e) 90  $\mu$ L, (f) 180  $\mu$ L, and (g) 270  $\mu$ L of NH<sub>4</sub>OH, and (i) UV-Visible spectra. TEM images of the surface of CTAB-AuNRs@SiO<sub>2</sub> prepared using (i) MeOH, (j) EtOH, and (k) IPA, and (l) UV-Visible spectra.



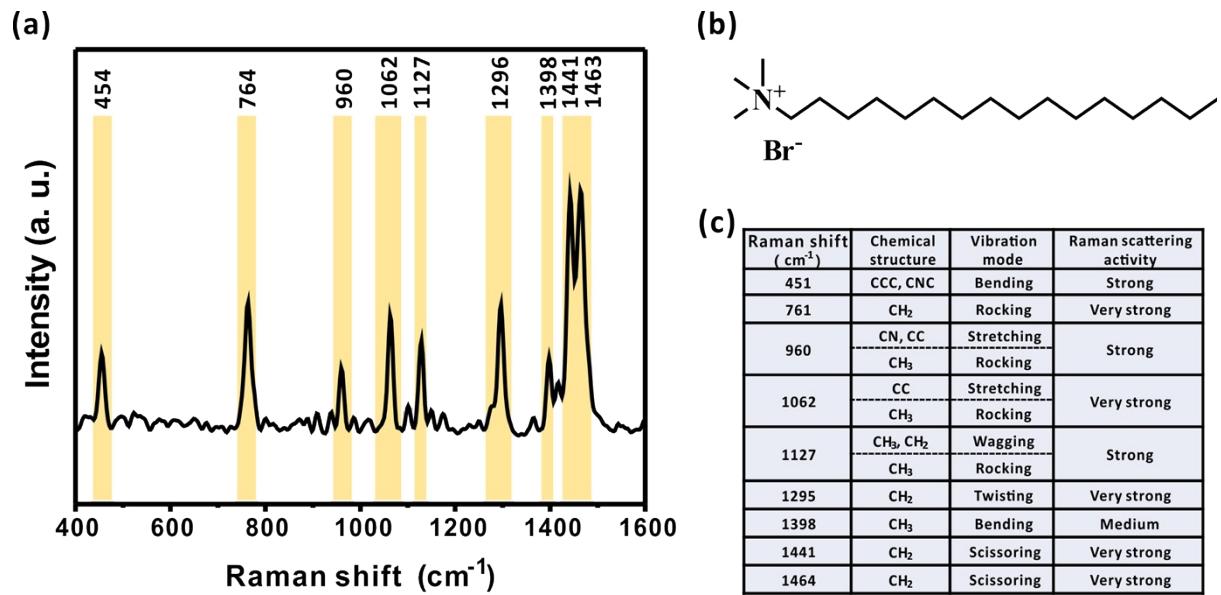
**Figure S2.** (a) UV spectra of CTAB-AuNRs and AuNR@SiO<sub>2</sub> with 5, 10, 15, 20, 25, 30, 35, and 40 nm SiO<sub>2</sub> shells, (b) changes of  $\lambda_{\max}$  of the CTAB-AuNRs and AuNR@SiO<sub>2</sub> with 5, 10, 15, 20, 25, 30, 35, and 40 nm SiO<sub>2</sub> shells.



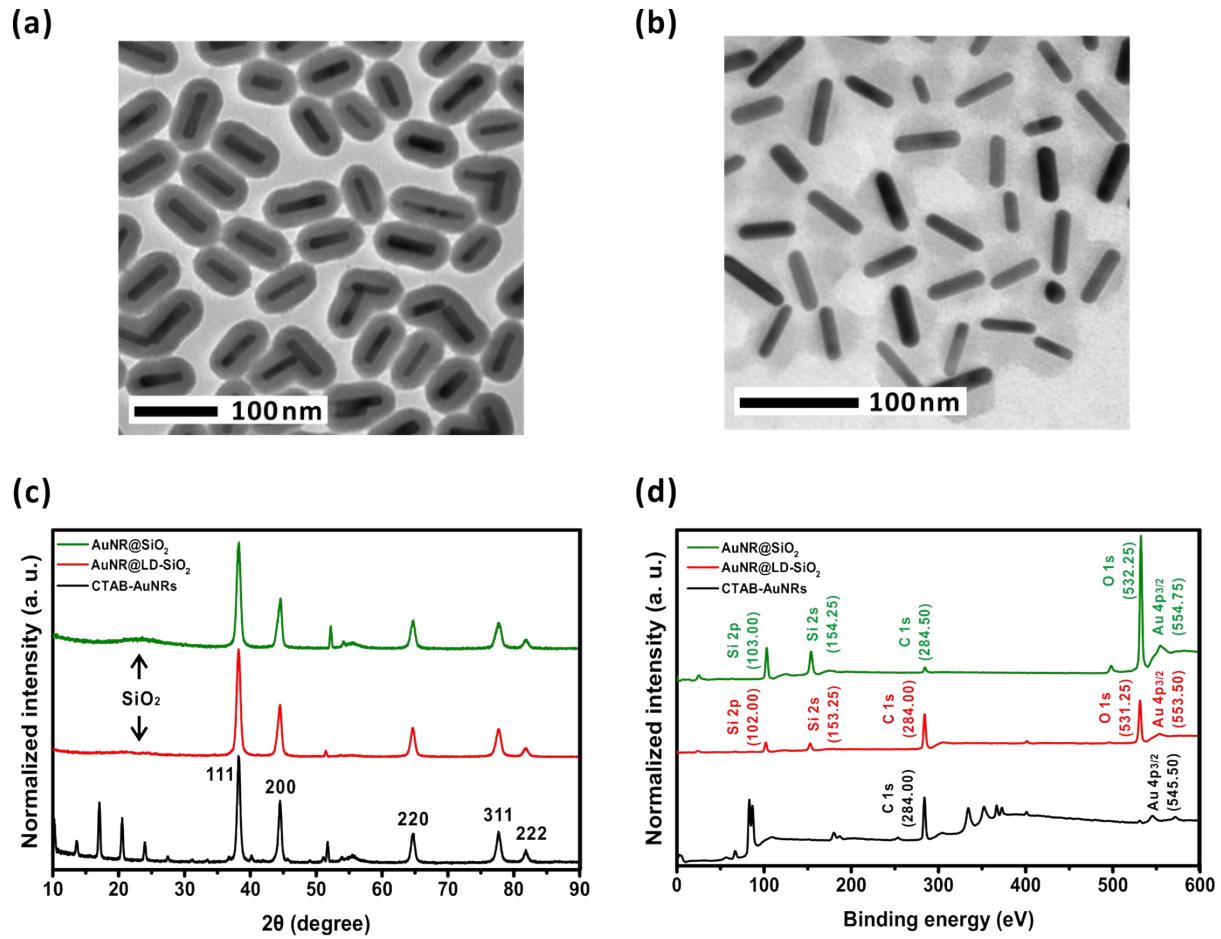
**Figure S3.** Experimental setup of the 808 nm CW laser at a power density of 1.25 W/cm<sup>2</sup>.



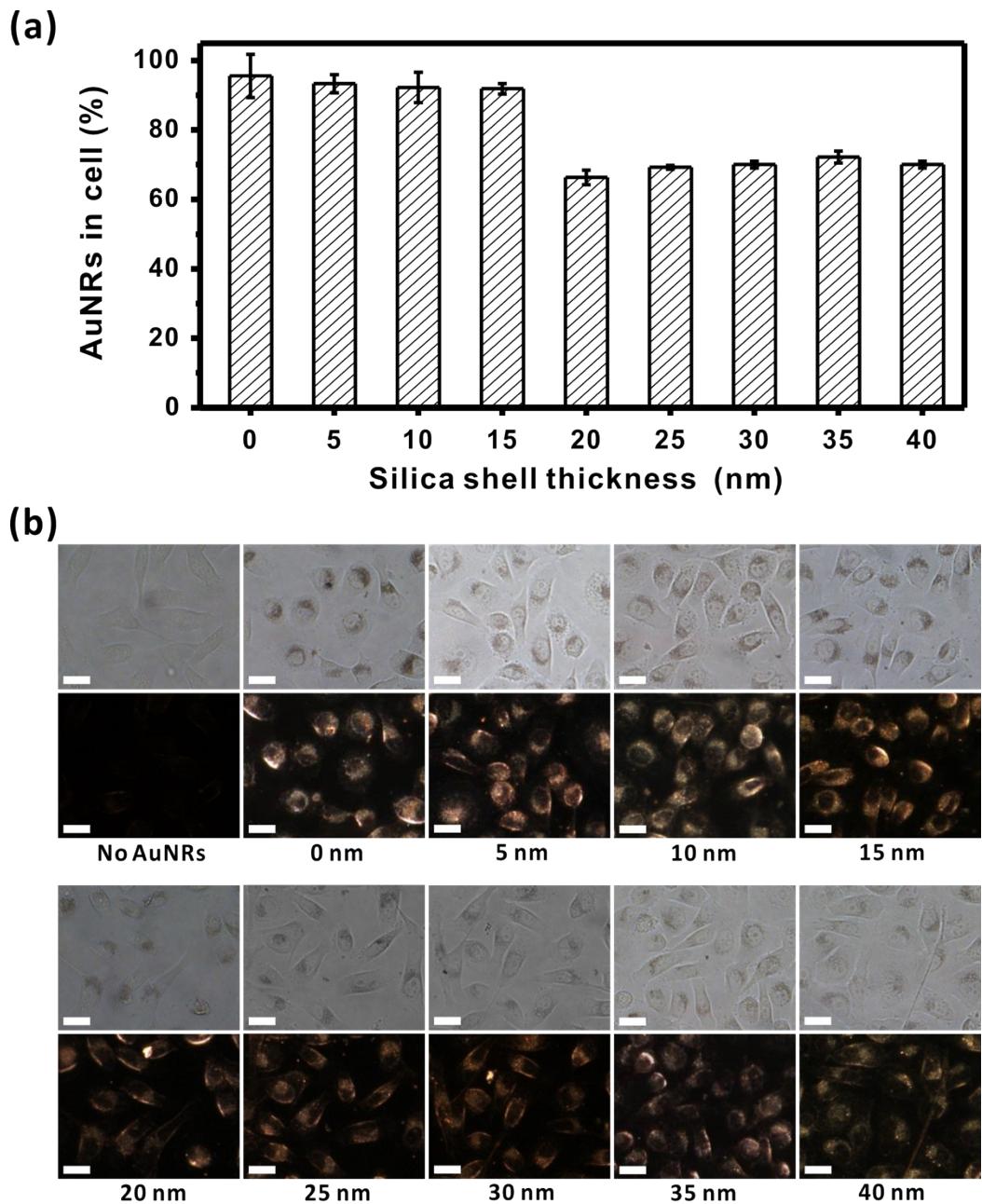
**Figure S4.** (a) Cooling curves of DW, CTAB-AuNRs, and AuNR@SiO<sub>2</sub>. Time constants ( $\tau_s$ ) and photothermal conversion efficiencies ( $\eta$ ) of (b) CTAB-AuNRs and AuNR@SiO<sub>2</sub> ((c) 5, (d) 10, (e) 15, (f) 20, (g) 25, (h) 30, (i) 35, and (j) 40 nm) for heat transfer from the system.



**Figure S5.** (a) Raman spectrum, (b) chemical structure, and (c) vibration modes of CTAB.<sup>1</sup>



**Figure S6.** TEM images of the as-prepared (a) AuNR@SiO<sub>2</sub> and (b) AuNR@LD-SiO<sub>2</sub>; (c) X-ray diffraction patterns and (d) X-ray photoelectron spectroscopy spectra of the CTAB-AuNRs (black line), AuNR@LD-SiO<sub>2</sub> (red line), and AuNR@SiO<sub>2</sub> (green line).



**Figure S7.** (a) Content of the AuNRs (OD = 1.5) in the cells measured at 780 nm and (b) bright-field and dark-field images of cells incubated with CTAB-AuNRs and AuNR@SiO<sub>2</sub> with defined silica shell thicknesses (5, 10, 15, 20, 25, 30, 35, and 40 nm).

## REFERENCES

1. H. Gokce, S. Bahceli, *Opt. Spectrosc.*, 2013, **115**, 632-644.